Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/734,226	LEE ET AL.	
Examiner	Art Unit	
Fric B Chen	1765	

SEARCHED							
Class	Subclass	Date	Examiner				

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
		•	

SEARCH NOT (INCLUDING SEARCH))
	DATE	EXMR
Performed inventor search for double patenting (PALM, eDAN)	7/13/2005	EC
EAST (all databases - see search history printout)	7/14/2005	EC
438/3,706,710,719,720,911 (text search only - see search history printout) (consulted L. Vinh - AU 1765)	7/14/2005	EC